MOTOROLA

MC14014B
MC14021B

CMOS MSI
(LOW-POWER COMPLEMENTARY MOS)

8-BIT STATIC SHIFT REGISTER

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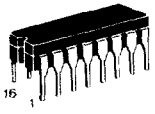
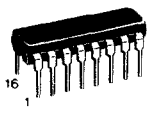
The MC14014B and MC14021B 8-bit static shift registers are constructed with MOS P-channel and N-channel enhancement mode devices in a single monolithic structure. These shift registers find primary use in parallel-to-serial data conversion, synchronous and asynchronous parallel input, serial output data queueing; and other general purpose register applications requiring low power and/or high noise immunity.

- Synchronous Parallel Input/Serial Output (MC14014B)
- Asynchronous Parallel Input/Serial Output (MC14021B)
- Synchronous Serial Input/Serial Output
- Full Static Operation
- "Q" Outputs from Sixth, Seventh, and Eighth Stages
- Double Diode Input Protection
- Supply Voltage Range = 3.0 Vdc to 18 Vdc
- Capable of Driving Two Low-power TTL Loads or One Low-power Schottky TTL Load Over the Rated Temperature Range
- MC14014B Pin-for-Pin Replacement for CD4014B
- MC14021B Pin-for-Pin Replacement for CD4021B



L SUFFIX
CERAMIC PACKAGE
CASE 620



P SUFFIX
PLASTIC PACKAGE
CASE 648

ORDERING INFORMATION

A Series: – 55°C to + 125°C
MC14XXXBAL (Ceramic Package Only)

C Series: – 40°C to + 85°C
MC14XXXBCP (Plastic Package)
MC14XXXBCL (Ceramic Package)

TRUTH TABLE

SERIAL OPERATION:

t	CLOCK	D_S	P/S	Q6 t = n+6	Q7 t = n+7	Q8 t = n+8
n		0	0	0	?	?
n+1		1	0	1	0	?
n+2		0	0	0	1	0
n+3		1	0	1	0	1
		X	0	Q6	Q7	Q8

PARALLEL OPERATION:

CLOCK		D_S	P/S	P_n	$^*Q_n$
MC14014B	MC14021B				
_/‾_	X	X	1	0	0
_/‾_	X	X	1	1	1

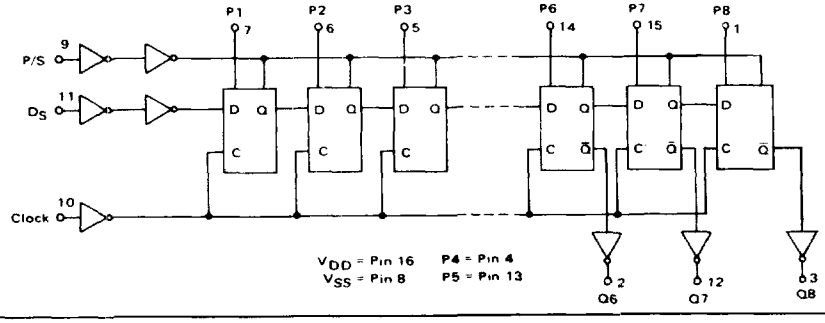
*Q6, Q7, & Q8 are available externally
X = Don't Care

MAXIMUM RATINGS* (Voltages Referenced to V_{SS})

Symbol	Parameter	Value	Unit
V_{DD}	DC Supply Voltage	– 0.5 to + 18.0	V
V_{in}, V_{out}	Input or Output Voltage (DC or Transient)	– 0.5 to V_{DD} + 0.5	V
I_{in}, I_{out}	Input or Output Current (DC or Transient), per Pin	± 10	mA
P_D	Power Dissipation, per Package†	500	mW
T_{stg}	Storage Temperature	– 65 to + 150	°C
T_L	Lead Temperature (8-Second Soldering)	260	°C

*Maximum Ratings are those values beyond which damage to the device may occur.
†Temperature Derating Plastic "P" Package: – 12mW/°C from 65 C to 85°C
Ceramic "L" Package 12mW/°C from 100°C to 125 C

LOGIC DIAGRAM



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ELECTRICAL CHARACTERISTICS (Voltages Referenced to V_{SS})

Characteristic	Symbol	V_{DD} Vdc	T_{low}* Min	T_{low}* Max	25°C Min	25°C Typ #	25°C Max	T_{high}* Min	T_{high}* Max	Unit
Output Voltage "0" Level	V_{OL}	5.0	–	0.05	–	0	0.05	–	0.05	Vdc
V_{in} = V_{DD} or 0		10	–	0.05	–	0	0.05	–	0.05	
		15	–	0.05	–	0	0.05	–	0.05	
"1" Level	V_{OH}	5.0	4.95	–	4.95	5.0	–	4.95	–	Vdc
V_{in} = 0 or V_{DD}		10	9.95	–	9.95	10	–	9.95	–	
		15	14.95	–	14.95	15	–	14.95	–	
Input Voltage "0" Level	V_{IL}									Vdc
(V_O = 4.5 or 0.5 Vdc)		5.0	–	1.5	–	2.25	1.5	–	1.5	
(V_O = 9.0 or 1.0 Vdc)		10	–	3.0	–	4.50	3.0	–	3.0	
(V_O = 13.5 or 1.5 Vdc)		15	–	4.0	–	6.75	4.0	–	4.0	
"1" Level	V_{IH}									
(V_O = 0.5 or 4.5 Vdc)		5.0	3.5	–	3.5	2.75	–	3.5	–	Vdc
(V_O = 1.0 or 9.0 Vdc)		10	7.0	–	7.0	5.50	–	7.0	–	
(V_O = 1.5 or 13.5 Vdc)		15	11.0	–	11.0	8.25	–	11.0	–	
Output Drive Current (AL Device)	I_{OH}									mAdc
(V_{OH} = 2.5 Vdc) Source		5.0	−3.0	–	−2.4	−4.2	–	−1.7	–	
(V_{OH} = 4.6 Vdc)		5.0	−0.64	–	−0.51	−0.88	–	−0.36	–	
(V_{OH} = 9.5 Vdc)		10	−1.6	–	−1.3	−2.25	–	−0.9	–	
(V_{OH} = 13.5 Vdc)		15	−4.2	–	−3.4	−8.8	–	−2.4	–	
(V_{OL} = 0.4 Vdc) Sink	I_{OL}	5.0	0.64	–	0.51	0.88	–	0.36	–	mAdc
(V_{OL} = 0.5 Vdc)		10	1.6	–	1.3	2.25	–	0.9	–	
(V_{OL} = 1.5 Vdc)		15	4.2	–	3.4	8.8	–	2.4	–	
Output Drive Current (CL/CP Device)	I_{OH}									mAdc
(V_{OH} = 2.5 Vdc) Source		5.0	−2.5	–	−2.1	−4.2	–	−1.7	–	
(V_{OH} = 4.6 Vdc)		5.0	−0.52	–	−0.44	−0.88	–	−0.36	–	
(V_{OH} = 9.5 Vdc)		10	−1.3	–	−1.1	−2.25	–	−0.9	–	
(V_{OH} = 13.5 Vdc)		15	−3.6	–	−3.0	−8.8	–	−2.4	–	
(V_{OL} = 0.4 Vdc) Sink	I_{OL}	5.0	0.52	–	0.44	0.88	–	0.36	–	mAdc
(V_{OL} = 0.5 Vdc)		10	1.3	–	1.1	2.25	–	0.9	–	
(V_{OL} = 1.5 Vdc)		15	3.6	–	3.0	8.8	–	2.4	–	
Input Current (AL Device)	I_{in}	15	–	±0.1	–	±0.00001	±0.1	–	±1.0	μAdc
Input Current (CL/CP Device)	I_{in}	15	–	±0.3	–	±0.00001	±0.3	–	±1.0	μAdc
Input Capacitance (V_{in} = 0)	C_{in}	–	–	–	–	5.0	7.5	–	–	pF
Quiescent Current (AL Device)	I_{DD}	5.0	–	5.0	–	0.005	5.0	–	150	μAdc
(Per Package)		10	–	10	–	0.010	10	–	300	
		15	–	20	–	0.015	20	–	600	
Quiescent Current (CL/CP Device)	I_{DD}	5.0	–	20	–	0.005	20	–	150	μAdc
(Per Package)		10	–	40	–	0.010	40	–	300	
		15	–	80	–	0.015	80	–	600	
Total Supply Current**† (Dynamic plus Quiescent, Per Package) (C_L = 50 pF on all outputs, all buffers switching)	I_T	5.0	I_T = (0.75 μA/kHz) f + I_{DD}							μAdc
		10	I_T = (1.50 μA/kHz) f + I_{DD}							
		15	I_T = (2.25 μA/kHz) f + I_{DD}							

*T_{low} = −55°C for AL Device, −40°C for CL/CP Device.
T_{high} = +125°C for AL Device, +85°C for CL/CP Device.

#Data labelled "Typ" is not to be used for design purposes but is intended as an indication of the IC's potential performance.

**The formulas given are for the typical characteristics only at 25°C.

†To calculate total supply current at loads other than 50 pF:

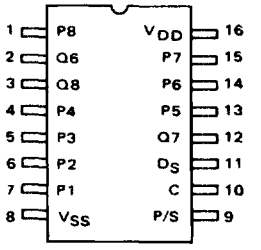
$$I_T(C_L) = I_T(50\ pF) + (C_L - 50)\ Vfk$$

where: I_T is in μA (per package), C_L in pF, V = (V_{DD} − V_{SS}) in volts, f in kHz is input frequency, and k = 0.0015.

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high-impedance circuit. For proper operation, V_{in} and V_{out} should be constrained to the range $V_{SS} \leq (V_{in}$ or $V_{out}) \leq V_{DD}$.

Unused inputs must always be tied to an appropriate logic voltage level (e.g., either V_{SS} or V_{DD}). Unused outputs must be left open.

PIN ASSIGNMENT



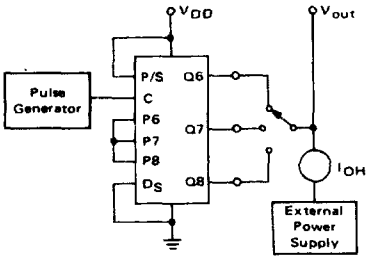
SWITCHING CHARACTERISTICS (C_L = 50 pF, T_A = 25°C)

Characteristic	Symbol	V_{DD} Vdc	Min	Typ #	Max	Unit
Output Rise and Fall Time	t_{TLH},					ns
t_{TLH}, t_{THL} = (1.5 ns/pF) C_L + 25 ns	t_{THL}	5.0	—	100	200	
t_{TLH}, t_{THL} = (0.75 ns/pF) C_L + 12.5 ns		10	—	50	100	
t_{TLH}, t_{THL} = (0.55 ns/pF) C_L + 9.5 ns		15	—	40	80	
Propagation Delay Time (Clock to Q, P/S to Q)	t_{PLH},					ns
t_{PHL}, t_{PLH} = (1.7 ns/pF) C_L + 315 ns	t_{PHL}	5.0	—	400	800	
t_{PHL}, t_{PLH} = (0.66 ns/pF) C_L + 137 ns		10	—	170	340	
t_{PHL}, t_{PLH} = (0.5 ns/pF) C_L + 90 ns		15	—	115	230	
Clock Pulse Width	t_{WH}	5.0	400	150	—	*ns*
		10	175	75	—	
		15	135	40	—	
Clock Frequency	f_{cl}	5.0	—	3.0	1.5	MHz
		10	—	6.0	3.0	
		15	—	8.0	4.0	
Parallel/Serial Control Pulse Width	t_{WH}	5.0	400	150	—	ns
		10	175	75	—	
		15	135	40	—	
Setup Time	t_{su}	5.0	200	100	—	ns
P/S to Clock		10	100	50	—	
		15	80	40	—	
Hold Time	t_h	5.0	20	−2.5	—	ns
Clock to P/S		10	20	−10	—	
		15	25	0	—	
Setup Time	t_{su}	5.0	350	150	—	ns
Data (Parallel or Serial) to		10	80	50	—	
Clock or P/S		15	60	30	—	
Hold Time	t_h	5.0	45	0	—	ns
Clock to D_S		10	35	0	—	
		15	35	5	—	
Hold Time	t_h	5.0	50	25	—	ns
Clock to P_n		10	45	20	—	
		15	45	20	—	
Input Clock Rise Time	$t_{r(cl)}$	5.0	—	—	15	µs
		10	—	—	5	
		15	—	—	4	

*The formulas given are for the typical characteristics only at 25°C.

#Data labelled "Typ" is not to be used for design purposes but is intended as an indication of the IC's potential performance.

FIGURE 1 – OUTPUT SOURCE CURRENT TEST CIRCUIT



Preset output under test to a logic "1" level.

FIGURE 2 – OUTPUT SINK CURRENT TEST CIRCUIT

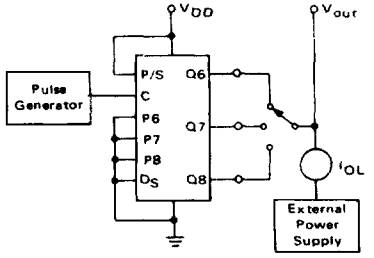


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FIGURE 3 – POWER DISSIPATION TEST CIRCUIT AND WAVEFORM

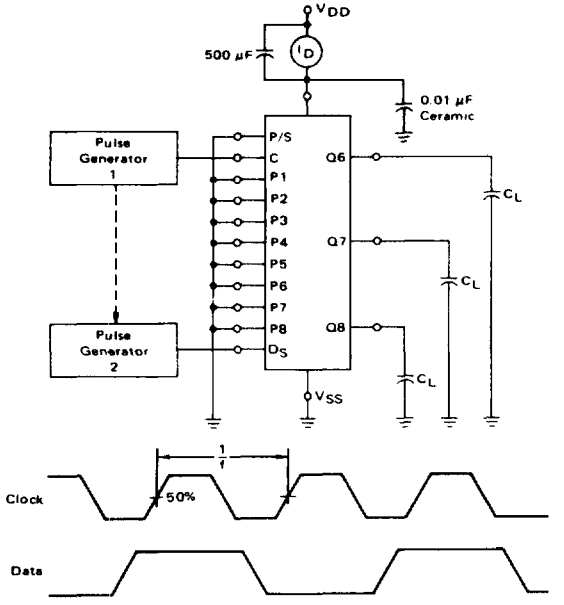

FIGURE 4 – SWITCHING TIME TEST CIRCUIT AND WAVEFORMS